

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/540,527	INOUE ET AL.	
Examiner	Art Unit	
John P. Sheehan	1793	

	SEARCHED					
Class	Subclass	Date	Examiner			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH N (INCLUDING SEARC	OTES CH STRATEGY	·)
·	DATE	EXMR
PALM Inventor Name Search	1/15/2008	JPS
East Search	1/16/2008	JPS